Keysight Technologies High-Resolution LXI Digitizers L4532A 2-channel, 20 MSa/s, 16-bit, ± 250 V L4534A 4-channel, 20 MSa/s, 16-bit, ± 250 V





High-Resolution LXI Digitizers

The Keysight Technologies's L4532A and L4534A are high-resolution, stand-alone LXI digitizers. They offer 2 or 4 channels of simultaneous sampling at up to 20 MSa/s, with 16 bits of resolution. Inputs are isolated and can measure up to ± 250 V to handle your most demanding applications.

Input channels with the ability to measure waveforms up to 250 V are ideal for analyzing high-voltage and transient signals such as those seen in automotive and aerospace defense applications. Most oscilloscopes and PXI digitizers have a maximum input range less than 40 Vpk. The ± 250 V input range of the L4532A and L4534A is combined with 16-bit analog-to-digital converters (ADCs), so the isolated front-end and low input offset allows a small voltage, such as a 250 mV, and a larger voltage, such as 250 V, to be measured at the same time.

The digitizers are LXI Class C compliant providing the benefits of an Ethernet connection, standard software drivers, an enhanced web interface, and more. Multiple vendors support the LXI standard making it easy to integrate the digitizers into your test system.

Save test time and money with high-performance analog inputs

The digitizer's individually isolated channel inputs have been designed for high performance with an ADC for each channel to ensure the signals you measure are accurately digitized without distortion or additional noise. Channel input range is configurable from ± 250 mV up to ± 250 V, with a floating voltage up to ± 40 V to accommodate differential waveform acquisition. You can also choose to enable 2 MHz and 200 KHz input filters to your digitizer. The high voltage input, isolated inputs, and selection of noise filters reduce the need to add expensive input signal attenuation and signal conditioning circuitry, saving test development time and money.

The 16-bit dynamic range combined with the ±250 V range is an advantage for test throughput since there is no need to make repeated "passes" with different range settings to capture both the smaller waveform details and larger waveform signals.

Minimize post processing with onboard measurements

The L4532A and L4534A digitizers include a collection of on-board "scope-like" measurements such as Vmin/Vmax, Vp-p, frequency, rise/fall time, and more that can be applied to a selected portion or the overall waveform. There is no need for post processing data to get the measurement results you need, saving time and minimizing the need to transfer and store large amounts of data. The waveform measurements are made within a user-selected region of the digitized waveform and include their time position. The following measurements are supported by the digitizers:

- V min/V max
- VPP
- V avg/V rms
- V top/V base
- Rise/fall time
- Overshoot/preshoot
- Frequency/period
- Pulse width
- Duty cycle

Key features

- Up to 20 M samples per second sample rate
- 16-bit ADC resolution
- 2 or 4 simultaneously sampled channels
- ±250 mV to ±250 V isolated inputs
- AC or DC coupling
- On-board measurements
- Built-in web interface
- 1U, full-rack standalone instrument
- Gigabit LAN and USB 2.0 interfaces
- Standard 32 MSa/ch or extended 128 MSa/ch segmented memory
- LXI Class C compliant

Easy-to-use graphical web interface

Connect to the digitizers' graphical web interface either by direct LAN or the Internet with your PC's Java-enabled web browser (such as Internet Explorer). Enter the IP address displayed on the front of the digitizer into the web browser address and you will be able to configure, acquire, and display waveforms and measurements without programming. The web interface simultaneously displays the channel signals and measurements, and provides an instrument command log that is very useful during development or debug.

The digitizer's web interface is easy to use, even from remote locations. The setup digitizer window allows you to select the configuration including sample rate, voltage range, record size, trigger source, and trigger mode. The acquire data window displays the waveforms and measurements. The waveform display has a similar look and feel to an oscilloscope with adjustable vertical and horizontal views. Markers allow you to select a portion of the waveform to make measurements on or view the waveform more closely.

The web interface records and displays the digitizers' instrument commands you select in the setup window. The list of instrument commands can be copied and pasted directly into your test program to expedite your test development.

Deep memory for flexible data acquisition

The L4532A and L4534A digitizers include a deep memory option (up to 128 MSa per channel) providing flexible waveform data acquisition. The waveform data collected is determined by the user and digitizer configuration including sample rate, segmented memory, flexible trigger system, and data reduction feature for data transferred from memory.

Segmented memory is used for sampling multiple bursts of readings. Memory can be segmented in 1 to 1024 records. Multiple records allow multiple bursts of data to be digitized without the need to re-initialize between bursts. The record size is configured by selecting the total number of samples including pre-trigger samples.

A flexible trigger system allows you to capture only the data you need. Trigger events are used to initialize the digitization of data for each record. Configurable trigger delay and trigger holdoff allow you to better define where record data is collected relative to the trigger event.

When retrieving digitized data users can take advantage of the built-in data reduction feature. This allows you to reduce the amount of unnecessary data through data decimation on select channels that were sampled at a faster rate than necessary.



Configurable sample rates

Based on a 20 MHz sample clock, the L4532A and L4534A allow you to select the desired sample rate on each channel. The sample rate is configurable from 1 KS/s to 20 MSa/s.

External clock (reference clock 10 MHz)

The clock in/out allows synchronizing system clocks of multiple instruments. When used with the external trigger, the synchronized instrument clocks allow multiple digitizers to sample in a synchronized lock step.

Flexible triggering

The digitizer's flexible trigger capability allows you to digitize samples in close proximity to the data of interest, reducing the overall data that needs to be digitized. Each trigger event causes completion of the current record's post trigger samples. The configurable trigger delay feature allows precise positioning of acquisition relative to the trigger event, while the trigger hold-off feature allows avoiding false triggers.

The external TTL trigger output enables L4532A and L4534A digitizers to synchronize to other devices. Multiple L4532A and L4534A digitizers can be synchronized for higher channel count. The digitizers provide an arm-trigger model you can use to pace groups of records (groups of triggers) by gating them through arm events that are different than trigger events. The fast re-arm feature reduces the dead-time between records, thus reducing the likelihood of missing a trigger event.

Built-in self-test ensures proper operation

A built-in self-test ensures proper operation of all major subsystems of the digitizer and reports any errors. A high-level self-test automatically runs at startup, or a more thorough self-test can be initiated on command. Successful completion indicates the digitizer is ready to use.

Easy, semi-automatic calibration

Calibration is easily achieved using a 6.5 digit DMM to measure the Cal Src Out on a few defined ranges of the digitizer. Simply send a command, using your programming language of choice or the web interface, that contains the measured source values to the digitizer, and the rest of the calibration is done automatically.

Gigabit ethernet for high-speed connection

The gigabit ethernet interface offers a high-speed connection that enables remote access and control of the digitizer. You can set up a private network to filter out unwanted LAN traffic and speed up the I/O throughput, or take advantage of the remote capabilities and distribute your tests worldwide. The Ethernet interface along with the web interface enables you to configure, monitor, and debug your application remotely.

The digitizers ship with Keysight E2094N I/O Libraries Suite making it easy for you to configure and integrate Keysight and other vendors' instruments into your system.

Standard software environments supported

Full support for standard programming environments ensures compatibility and efficiency. The digitizers can be automated using SCPI or standard IVI and LabVIEW software drivers that provide compatibility with the most popular development environments:

- Keysight Microsoft Visual Studio .NET, Keysight VEE Pro, Microsoft C/C++, Visual Basic
- National Instruments LabVIEW, LabWindows/CVI, Test Stand

Specifications

L4532A (2 channel) or L4534A (4 channel) digitizers with ADCs per channel

Max sample rate	20 MSa/s	
Sample resolution	16 Bits	
Input configuration	Isolated inputs (each channel	
	independently isolated)	
Isolation voltage	±40 V	
(low to chassis)		
Maximum input (Hi to Low)	±250 Vpk1	
Maximum input range	±256 V	
Input impedance	1 M Ω in parallel with 40 pF	
Input coupling	DC or AC	
AC cutoff freq (-3 dB)	< 10 Hz	
Input ranges:	±256 V, ±128 V, ±64 V, ±32 V,	
	±16 V, ±8 V, ±4 V, ±2 V, ±1 V, ±500	
	mV, ±250 mV	
Over voltage protection	Yes	
Maximum overvoltage	±400 Vpk	
transient		
Analog bandwidth (-3 dB)	20 MHz typical	
Noise filtering (2-pole	200 KHz, 2 MHz typical	
Bessel)		
Power requirements		
Line voltage	100 to 240 VAC (universal)	
Line frequency	50 Hz or 60 Hz	
Power consumption	45 W (100 VA)	
Safety conforms to		
IEC/EN 61010-1:2001(EL	(L	
CAN/CSA-C22.2 No. 610	10-1-04 (Canada)	
UL 61010-1 (2nd Edition) (US)		
AS 61010.1:2003 (Austral	lia/New Zealand)	
EMC conforms to		
IEC 61326-1:2005-12 (EU)		
EN 61326-1:2006		
ICES-001:2004 (Canada)		
AS/NZS CISPR 11:2004		

Arm and trigger

Each Arm event gates one or more trigger events. Each trigger event causes acquisition of data into a single record at the configured sample rate. The number of data records is configurable from 1 to 1024.

Source	ARM Trigger	Description
IMMediate	• •	Trigger or ARM at INIT time
EXTernal ²	• •	BNC TTL input edge
		(selectable rising/falling edge
Software	• •	Instrument commands
Timer	•	0.0 s to 3600.0 s with
		50 ns resolution
Channel/Edge	•	Selectable level, rising/falling,
		hysteresis
Channel/Window	/	Selectable high and low levels,
		leaving/entering, hysteresis
OR ³	•	Logical OR of channel trigger
		source and External
Sampling		
Programmable sa	ample 1	KSa/s, 2 KSa/s, 5 KSa/s,
rates	1(0 KSa/s, 20 KSa/s, 50 KSa/s, 100
	K	Sa/s, 200 KSa/s, 500 KSa/s,
	1	MSa/s, 2 MSa/s, 5 MSa/s,
<u> </u>][U MSa/s, 20 MSa/s
External event ou	utput –	
Event types:	11	rigger, end-ot-record,
	ei	nd-of-acquisition
Output signal:	4,5	IL (rising edge)
Impedance:	2	5 ohm or 50 ohm
Irigger modes	0	
Pre-trigger	0	to record length minus 4
Post-trigger	R	ecord length minus pre-trigger
l imestamp trig	ggered E	lapsed time since INII, or CONTinu-
event	01	us running timestamp
Limestamp res	solution I	2.5 ns
I rigger delay	0	- 3600 s with 50 ns resolution
Trigger holdof	f 0	– 10 s with 50 ns resolution
I rigger latency	/° 1.	2.5 NS
Irigger reactive		
Ext input trigg	er latency 40	Unstoblins
Ext output trig	ger 4	ns to 21 ns
latency		

CAT I IEC measurement Category I. Inputs may be connected only to circuits that are isolated from AC mains.
EXTernal can be used as an ARM source or a trigger source, but not both at the same time.
OR can only be used if the EXTernal source is being used as a trigger source.

- 4. 5. 4.
- Pulse width 1 μ s (200 ns for records taking <2 μ s to complete). TTL output pulse can be configured for either rising or falling edge. 5.
- 6. 6. Latency between level/window trigger detection and first (trigger) sample.

Accuracy¹

Tota	l specification	(%	of	reading	+ %	6 of rang	je). ²

	23 °C	±5°C	T _{autozero} ±3 °C ^E	5	Temp co	efficient 18-28 °C	outside
Range	±% of	±% of	±% of	F	±% of	±۶	6 of
	reading	range	range		reading/C	ran	ge/C
250 mV	0.10	0.30	0.11		0.010	0.0)15
500 mV	0.10	0.20	0.06		0.010	0.0	010
1 V, 2 V	0.10	0.12	0.04		0.010	0.0	010
4 V, 64 V	0.10	0.30	0.05		0.010	0.0	015
8 V, 128 V	0.10	0.20	0.04		0.010	0.0	010
16 V, 32 V, 256 V	0.10	0.12	0.04		0.010	0.0)10
Integral no	nlinearit	у	±5 LS	SΒ			
Differential	nonline	arity	±1 LS	SB ty	/pical, no r	nissing c	odes
Input bias	current		< 10	nA t	ypical		
Dvnamic Ch	aracteris	tics ⁴ (tv	pical)				
(Measured u	using a 65	5536 poi	nt FFT)				
Input range	980 kHz	input (-	1 dBFS)				
	SFD	R TH	D SN	IR	SINAD	ENOB ³	
	(dBc	:) (-d	Bc) (db)	(db)		
250 mV	71	79	67		66.7	10.8	
500 mV	77	83	70		69.8	11.3	
1 V	81	85	73		72.7	11.8	
2 V	85	82	75		74.2	12.0	
4 V	70	80	64		63.9	10.3	
8 V	70	83	65		64.9	10.5	
16 V	70	81	65		64.9	10.5	
Input range	10 MHz	input (-1	dBFS)				
250 mV	71	71	66		64.8	10.5	
500 mV	71	73	68		66.8	10.8	
1 V	69	68	72		66.5	10.8	
2 V	63	62	72		61.6	9.9	
AC flatness	s (DC-4 I	MHz)					
250 mV			±0.28	3 dB	relative to	o 1 kHz	
500 mV, 16 V. 3	1 V, 2 V 32 V	,4V,8	V, ±0.20) dB	relative to	o 1 kHz	
64 V. 12	8 V. 256	V	±0.40) dB	(±0.01 dE	8∕ °C terr	perature
,	.,_50		coeff	icier	nt outside1	8-28 °C) relative
			to 1 k	(Hz	1 1 10.00	, _0 0	,
Crosstalk (Ch to Ch	1)	<-90	dB	@ 1 MH7		
R = 50 Oh	m	,	. 50		<u> </u>		

Timing and synchronization	
Internal timebase accuracy	±50 ppm
Internal timebase output	
(Clock out BNC)	
Frequency	10 MHz
Level	>1 Vpp
External timebase reference	
(Clock in BNC)	
Lock range	10 MHz ±5000 pp (10 MHz ±50 kHz)
Clock lock skew (typical)	±10 ns (typical)
Level	1 Vpp sinewave min <2 psec rms jitter
Input resistance nominal	100 kΩ nominal
Synchronizing multiple digitizers	Use internal timebase source
Synchronized data sampling with	Sample rate settings of less than 20 MHz
multiple digitizers	produce data sample errors of up to ± 4 data samples (typical)
Waveform memory	
Data memory	
Standard ⁴	32 MSa/ch
Extended ⁴	128 MSa/ch
Random access to readings	Capture multiple records from multiple
Multiple record mode	triggers
Waveform measurements	
Voltage	Peak-to-peak, minimum, maximum, average, RMS, amplitude, base, top, overshoot, preshoot, upper, middle, lower
Time	Rise, fall, period, frequency, positive width, negative width, duty cycle
Utilities	
Calibration	
Calibration cvcle	1 vear
Internal calibration source	0 to ±16 V typical
Electronic calibration	Requires an external 6.5 digit DMM and PC
Self-test	Power on self-test, Complete test performed via *TST? command
Hardware	
1U full rack LXI	425.7 mm W x 44.5 H x 367.9 mm D
Weight	
L4532A (2-ch)	3.3 kg
L4534A (4-ch)	3.63 kg
Front panel	Power switch and display
Back panel (Connectors)	
Input channels	BNC
Cal Src Out	BNC
10 MHz In	BNC
10 MHz Out	BNC
Trig In/Out	BNC
I/O interface	LAN (Gbit), USB 2.0

- 100,000 reading average @ 1 MSa/s For 1 V range and greater, typical offset with constant temperature is 0.01% of range.
- External timebase measurements made with 1 Vpp sinewave with <2 ps RMS jitter.

 ENOB = (SINAD - 1.76)/6.02
Nominal values. Specific sample max is 33,554,432 and 134,205,440 samples.

Software			
Web interface:	Internet Explorer or Mozilla Firefox.		
	Requires Java 8 or greater.		
Programming language:	ASCII commands, IEEE 488.2 compliant		
Computer interfaces:			
LAN: Standard LAN	(VXI-11* compliant),		
10/100/1000BaseTx	Sockets (service at port 5025), Telnet		
	(service at port 5024))		
USB: Standard USB 2.0	(USBTMC** compliant)		
Programming via direct native c	ommand set:		
VISA IO control (LAN or USB)	Keysight IO Libraries Suite 15.0		
	or greater recommended		
LAN sockets control	<sockets programming=""></sockets>		
(LAN only)			
Programming via software driver:			
IVI-COM, IVI-C Driver for Window 2000/XP/Vista, G driver for			
LabVIEW			
Compatible with programming tools and environments:			
Keysight VEE Pro, Microsoft Visual Studio.NET, C/C++,			
Visual Basic 6, National Instruments Test Stand,			
Measurement Studio, LabWindows/CVI, LabVIEW			
* VXI-11 allows transfer of IEEE 488.1 and IEEE 488.2 messages over a			
TCP/IP network. Supported by Keysight IO Library Suite (included).			
** USB Test and Measurement Class (TMC) that communicates over			
USB, complying with IEEE 488.1 and IEEE 488.2 standards. Supported by			
Keysight IO Library Suite (includ	ed).		

Minimum sys	stem requirements (I/O lib	oraries & drivers)
Operating	Windows XP SP2 (or	Windows Vista 32-bit (Home,
system	later) Windows 2000	Basic, Premium, Business,
	Professional	Ultimate, Enterprise)
	SP4 (or later)	
Processor	450 MHz Pentium II or	1 GHz 32-bit (x86)
	higher required; 800	
	MHz recommended	
Available	128 MB minimum,	512 MB minimum
memory	(256 MB or greater	(1 GB recommended)
	recommended)	
Available	280 MB minimum, 1 GB r	ecommended for Microsoft.NET
disk space	framework 2.0	
	65 MB for Keysight IO Lib	raries Suite
Video	Super VGA (800 x 600),	Support for Direct X 9 graphics
	256 colors or more	with 128 MB graphics memory
		recommended (Super VGA
		graphics is supported)
Browser	Microsoft Internet	Microsoft Internet Explorer 7 or
	Explorer 5.01 or greater	greater

Environmental	
Operational environment	Pollution degree 2, indoors
Operating temperature	0 to 55 °C
Storage temperature	-40 to+70 °C
Warm-up period	<60 min to rated specs
Relative humidity @ 40 °C	20 to 95% non-condensing
Vibration:	Keysight's ETM limits
Data storage/transfer	
Pre-trigger data	Up to full record length -4 samples
Record length	8 samples to 32 MSa/128 MSa
Post-trigger data	4 samples to 128 MSamples
Maximum number of triggers	Number of records (triggers) configurable
	to 1024 records
Resolution	One sampling interval
Timestamp rollover	>1.5 years
Maximum data transfer rate	
from memory	
USB 2.0	8 MB/s
Gbit LAN	15.0 MB/s ¹

1. In order to achieve this speed, several conditions must be met. Refer to specifications table in the May 2016 (or later) user manual for detailed information.

Ordering Information

L4532A	2-channel 20 MSa/s digitizer
Opt 001	Standard memory (32 MS/ch)
Opt 002	Extended memory (128 MS/ch)
L4534A	4-channel 20 MSa/s digitizer
Opt 001	Standard memory (32 MS/ch)
Opt 002	Extended memory (128 MS/ch)
Includes produc	t reference CD (products doc and examples),
IO Libraries CD,	and power cord.
Accessories	
Opt 908	Rack mount kit L4532-67001
Option 0B0	Deletes printed manual set
	(Full documentation included on CD ROM)
Option ABA	English printed manual set

For additional information please visit: http://www.keysight.com/find/L4534A

Related Keysight Literature

Keysight VEE Pro, data sheet, literature number 5989-7427EN Keysight E2094N IO Libraries Suite, data sheet, literature number 5989-1439EN

Definitions for Specifications

Specifications describe the warranted performance of calibrated instruments that have been stored for a minimum of 2 hours within the operating temperature range of 0 to 55 °C, unless otherwise stated, and after a 60 minute warm-up period. Data represented in this document arespecifications unless other wise noted.

Characteristics describe product performance that is useful in the application of the product, but that is not covered by the product warranty. Characteristics are often referred to as Typical or Nominal values.

Typical describes characteristic performance, which 80% of the instruments will meet when operated over a 18 to 28 °C temperature range. Typical performance is not warranted.

Nominal describes representative performance that is useful in the application of the product when operated over a 18 to 28 °C temperature range. Nominal performance is not warranted. Note: All graphs contain measure data from several units at room temperature unless otherwise noted.

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LXI

www.lxistandard.org

LAN eXtensions for Instruments puts the power of Ethernet and the Web inside your test systems. Keysight is a founding member of the LXI consortium.



www.keysight.com/find/ThreeYearWarranty

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Hong Kong800 938 693India1 800 11 2626Japan0120 (421) 345Korea080 769 0800Malaysia1 800 888 848Singapore1 800 375 8100Taiwan0800 047 866Other AP Countries(65) 6375 8100

Europe & Middle East

United Kingdom

ngdom 0800 0260637

For other unlisted countries: www.keysight.com/find/contactus (BP-02-10-16)



www.keysight.com/go/quality Keysight Technologies, Inc. DEKRA Certified ISO 9001:2015 Quality Management System

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